

Notice of References Cited		Application/Control No. 10/589,784	Applicant(s)/Patent Under Reexamination HAYASHI ET AL.	
		Examiner Martin J. Angebranndt	Art Unit 1795	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2007/0200263 A1	08-2007	Tazaki et al.	264/002.5
*	B	US-2004/0027512 A1	02-2004	Kubomura et al.	349/65
*	C	US-2007/0211199 A1	09-2007	Kobayashi et al.	349/117
*	D	US-2008/0094845 A1	04-2008	Kusano et al.	362/339
*	E	US-2009/0059564 A1	03-2009	Tsukada et al.	362/97.1
*	F	US-2002/0125322 A1	09-2002	McCall et al.	235/462.42
*	G	US-3,698,810	10-1972	Bestenreiner et al.	355/71
*	H	US-3,619,021	11-1971	Biedermann et al.	359/15
*	I	US-4,336,978	06-1982	Suzuki, Takashi	359/599
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	62-203101	09-1987	Japan	Yoshimura	**
	O	08-327806	12-1996	Japan	Koujima et al.	**
	P	01-302204	12-1989	Japan	Kuwata et al.	**
	Q	08-036108	02-1996	Japan	Aoki et al.	***
	R	2003-286316	10-2003	Japan	Hasegawa et al.	***
	S	05-196808	08-1993	Japan	Fujiwara et al.	***
	T	2001-323074	11-2001	Japan	Mizuno et al.	***

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	V				
	W				
	X				

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